

| | | | |
|-----------------------------------|---------------------------------------|-----------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 09/950,038 | Applicant(s)/Patent Under Reexamination ZAIT ET AL. | |
| | Examiner Martin J Angebranndt | Art Unit 1756 | Page 1 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------|----------------|
| | A | US-6333485 | 12-2001 | Haight et al. | 219/121.68 |
| | B | US-5463200 | 10-1995 | James et al. | 219/121.68 |
| | C | US-4190759 | 02-1980 | Hongo et al. | 219/121M |
| | D | US-3889272 | 06-1975 | Lou et al. | 346/135 |
| | E | US-4727234 | 02-1988 | Oprysko et al. | 219/121L |
| | F | US-6190836 | 02-2001 | Grenon et al. | 430/311 |
| | G | US-6346352 | 02-2002 | Hayden et al. | 430/5 |
| | H | US-5208818 | 05-1993 | Gelbart et al. | 372/30 |
| | I | US-5830606 | 11-1998 | Okamoto | 430/5 |
| | J | US-5395718 | 03-1995 | Jensen et al. | 430/5 |
| | K | US-4923772 | 05-1990 | Kirch et al. | 430/5 |
| | L | US-4529991 | 07-1985 | Wada et al. | 346/76L |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-----------------------------------------------------------------------------------------------------------------------------------------------|
| | U | Ihleman et al. "Excimer laser ablation patterning of dielectric layers", Applied Surf. Sci., Vol. 86(1-4) pp. 228-233 (abstract only) |
| | V | Haight et al., "Implementation and performance of a femtosecond laser mask repair system in manufacturing", Proc. SPIE vol. 3546, pp. 477-484 |
| | W | Shani et al., "high resolution near field mask repair with femtosecond laser |
| | X | O'Connor et al. "Next generation laser based mask repair tool", Proc. SPIE vol. 1604 pp. 167-178 (1991) |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

09/950,038

Applicant(s)/Patent Under
Reexamination
ZAIT ET AL.

Examiner

Martin J Angebranndt

Art Unit

1756

Page 2 of 2

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|------|----------------|
| | A | US- | | | |
| | B | US- | | | |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|------------------------------------------------------------------------------------------------------------------------------------------------|
| | U | Haight et al., "MARS:Femtosecond laser mask advanced repair system in manufacturing", J Vac. Sci. Technol. B 17(6) pp 3137-3143 (Nov/Dec 1999) |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.